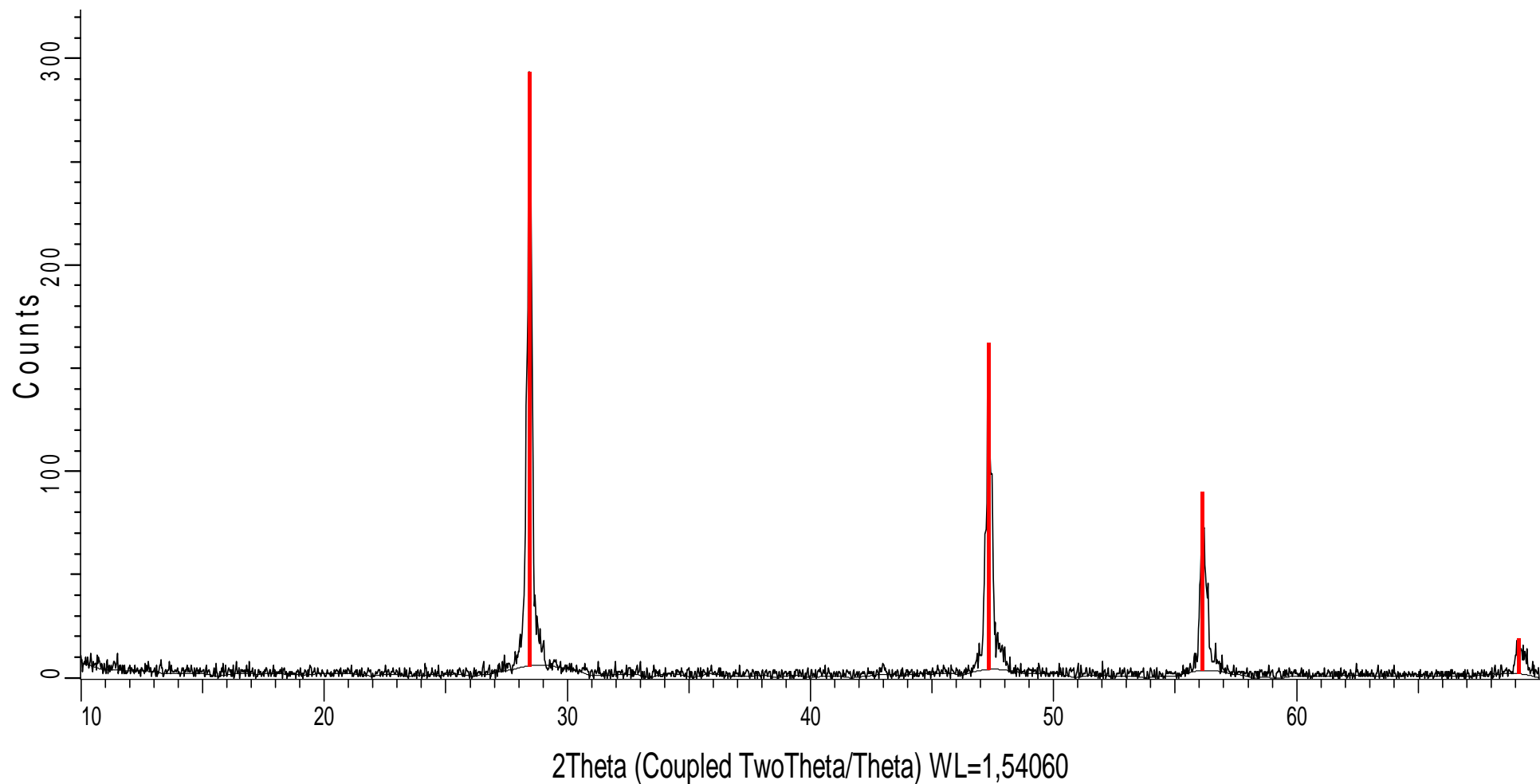


# PATRÓN DE SI NIST SRM 640C 22-03-12



- SI NIST XRK900 22-03-12. Barrido tipo  $\Theta$ - $\Theta$ . Rango: 10 a 70  $^{\circ}2\Theta$ . Paso: 0,03. Tiempo por paso: 1 seg. Cámara: XRK900 Detector: VANTEC.
- Patrón de SI NIST 640c. Cúbico – a 5.43088 - b 5.43088 - c 5.43088 -  $\alpha$  90.000 -  $\beta$  90.000 -  $\gamma$  90.000 – Centrado en las caras – Fd-3m (227) – Z 8 – V 160.181

# INFORME DE CALIBRACIÓN XRK900

Si NIST 640c D8C 22-03-12

Range Number : 1

## R-Values

Rexp : 42.94 Rwp : 43.06 Rp : 31.54 GOF : 1.00  
Rexp` : 52.10 Rwp` : 52.24 Rp` : 40.28 DW : 1.73

## Instrument

Primary radius (mm) 200.5  
Secondary radius (mm) 200.5  
Linear PSD 2Th angular range (°) 3  
FDS angle (°) 0.6  
Beam spill, sample length (mm) 14  
Intensity not corrected  
Full Axial Convolution  
Filament length (mm) 12  
Sample length (mm) 14  
Receiving Slit length (mm) 6  
Primary Sollers (°) 2.5  
Secondary Sollers (°) 4

## hkl Phase - 1 Lebail method

Phase name Silicio  
R-Bragg 3.547  
Spacegroup 227  
Cell Mass 0.000  
Cell Volume (Å<sup>3</sup>) 159.912(72)  
Wt% - Rietveld 0.000  
Crystallite Size  
Cry size Lorentzian (nm) 81(11)  
k: 1 LVol-IB (nm) 51.8(68)  
k: 0.89 LVol-FWHM (nm) 72.4(95)  
Strain  
Strain L 0.083(46)  
Strain G 0.00(32)  
e0 0.021(17)

## Lattice parameters

a (Å) 5.42784(82) **NIST 640c Certificate**  
**5.43311946(92)**

h	k	l	m	d	Th2	I
1	1	1	8	3.13377	28.45892	2.93
0	2	2	12	1.91903	47.33136	5.35
3	1	1	24	1.63656	56.15719	4.55
2	2	2	8	1.56688	58.89313	0.0678
0	0	4	6	1.35696	69.17501	1.88